There will be four breakout sessions to be held on Thurs afternoon of 6/24:

* One is focused on discussion of a specific technical issue for a high visibility flight program
* Three will be “ask the expert” sessions where a team of experts will be available to discuss where we are and where we’re going in future electronics related areas. Breakouts and session leaders are listed below. Please plan to attend. We will be polling attendees on which session they primarily plan on attending.

1. Verifying COTS avionics systems for high reliability applications in the SEE environment:   
   Can system architecture/redundancy combined with software error detection/correction/recovery defeat the need for testing? - Steve Koontz, JSC (participation with his approval only)  
   E-mail address: [steven.l.koontz@nasa.gov](mailto:steven.l.koontz@nasa.gov)
   1. Can generic upper limits be determined for correctable soft error rates?
   2. Can generic upper limits be determined for uncorrectable soft and hard error rates?
   3. How important is vendor piece-parts control and traceability?
   4. What kind of system test and analysis is needed for system verification and acceptance?
2. Sample size statistics and qualification – Alexander Teverosky and Ray Ladbury, GSFC
   1. A two-sided ask the experts session focused on discussing the statistical significance of samples size in lot qualification for both parts reliability and radiation perspective.
3. State-of-the-art semiconductors: the challenges for using in space - Doug Sheldon, JPL
   1. Ask the experts on what qualification really means for the future